

VDD OVER AND UNDERRVOLTAGE MEASUREMENT TECHNIQUES USING MONITOR CELLS

ABSTRACT OF THE DISCLOSURE

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According to one embodiment, a method of testing an integrated circuit is provided. A reference voltage is coupled to each of a first and second comparator integrated on the chip. A supply voltage is compared to the reference voltage in a comparator to determine overvoltage or undervoltage conditions. The results of the comparison are stored and sizing and placing of at least one decoupling circuit in the circuit design is made based on the stored determinations.

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